

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet

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of

2

Application Number

10/066,264

Filing Date

1/31/02

First Named Inventor

Steven Teig, et al.

Group Art Unit

2825

Examiner Name

LIU, ANDREA

Attorney Docket Number

SPLX.P0094

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
af	14.	D. Jongeneel, R. Otten, Y. Watanabe and R. K. Brayton, Area and Search Space Control for Technology Mapping, 37 th Design Automation Conference, 86-91, 2000.	
af	15.	Henrik Reif Andersen, An Introduction to Binary Decision Diagrams, October 1997 (minor revisions April 1998), 36 pp.	
af	16.	Jerry Burch and David Long, Efficient Boolean Function Matching, Proc. ICCAD 1992, 408-411.	
af	17.	John Fishburn, A Depth-Decreasing Heuristic for Combinational Logic; or How to Convert Ripple-Carry Adder into a Carry-Lookahead Adder or Anything In-Between, Proceedings of the 27 th Design Automation Conference, 361-364, 1990.	
af	18.	Kamal Chaudhary and Massoud Pedram, A Near Optimal Algorithm for Technology Mapping Minimizing Area under Delay Constraints, Proceedings of the 29 th Design Automation Conference, 492-498, 1992.	
af	19.	Kurt Keutzer, DAGON: Technology Binding and Local Optimization by DAG Matching, Proceedings of the 24 th Design Automation Conference, 341-347, 1987	
af	20.	Randal Bryant, Symbolic Boolean Manipulation with Ordered Binary Decision Diagrams, CMU CS Tech Report CMU-CS-92-160.	
af	21.	Uwe Hinsberger and Reiner Kolla, Boolean Matching for Large Libraries, Proceedings of the 35 th Design Automation Conference, 206-211, June 1998.	-
af	22.	Yuji Kukimoto, Robert K. Brayton, and Prashant Sawkar, Delay-Optimal Technology Mapping by DAG Covering, Dept. of Electrical Engineering and Computer Science, University of California, Berkeley, Strategic CAD Laboratories, Intel Corp., October 1997.	-
af	23.	Zbigniew J. Czech, et al., An Optimal Algorithm for Generating Minimal Perfect Hashing Functions, Information Processing Letters, 43(5); 257-264, October 1992	

Examiner
Signature*Andrea Liu*Date
Considered

9/3/03

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RELATED U.S. PATENT APPLICATIONS

Examiner* Initials	Cite No. ¹	U.S. Patent Application		Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Serial Number				
AT	1.	10/062,017		Steven Teig & Asmus Hetzel	01-31-02	
AT	2.	10/061,459		Steven Teig & Asmuz Hetzel	01-31-02	
AT	3.	10/062,014		Steven Teig & Asmus Hetzel	01-31-02	
AT	4.	10/062,044		Steven Teig & Asmuz Hetzel	01-31-02	
AT	5.	10/066,188		Steven Teig & Asmus Hetzel	01-31-02	
AT	6.	10/062,992		Steven Teig & Asmus Hetzel	01-31-02	
AT	7.	10/061,474		Steven Teig & Asmuz Hetzel	01-31-02	
AT	8.	10/061,719		Steven Teig & Asmus Hetzel	01-31-02	
AT	9.	10/066,456		Steven Teig & Asmus Hetzel	01-31-02	
AT	10.	10/062,993		Steven Teig & Asmus Hetzel	01-31-02	
AT	11.	10/062,047		Steven Teig & Asmuz Hetzel	01-31-02	

U.S. PATENT DOCUMENTS

Examiner* Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
AT	12.	5,649,165		Jain et al.	07-15-97	
AT	13.	6,301,687	B1	Jain et al.	10-09-01	

Examiner Signature	<i>Andrea Liu</i>	Date Considered	9/3/03
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